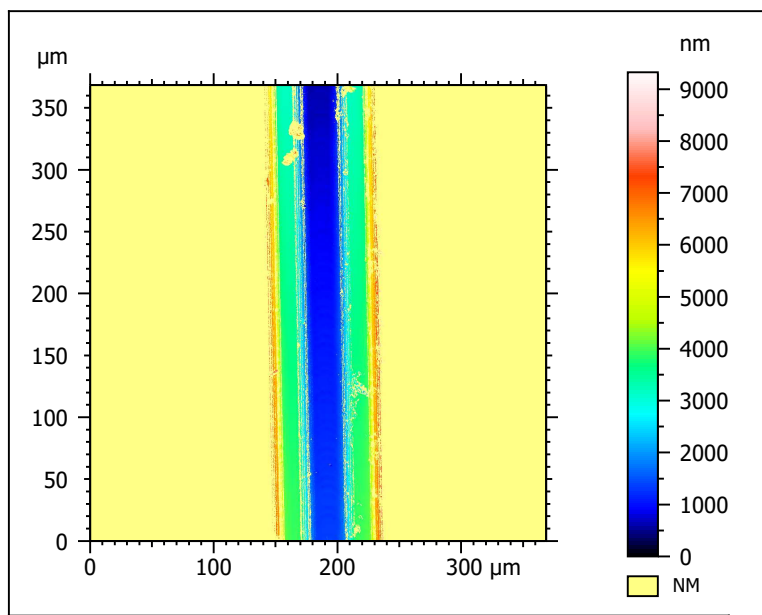
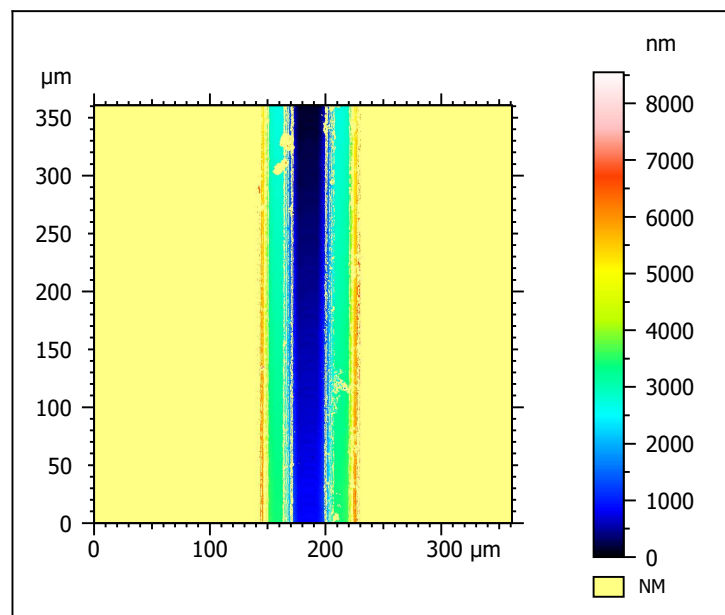
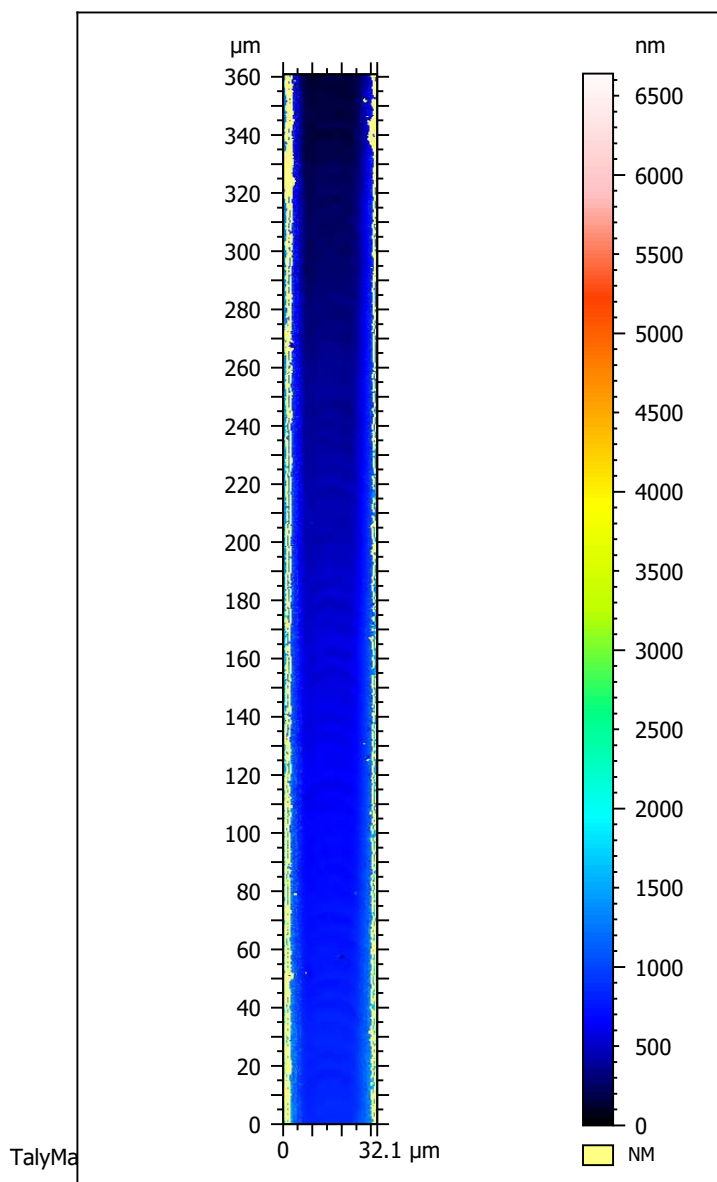


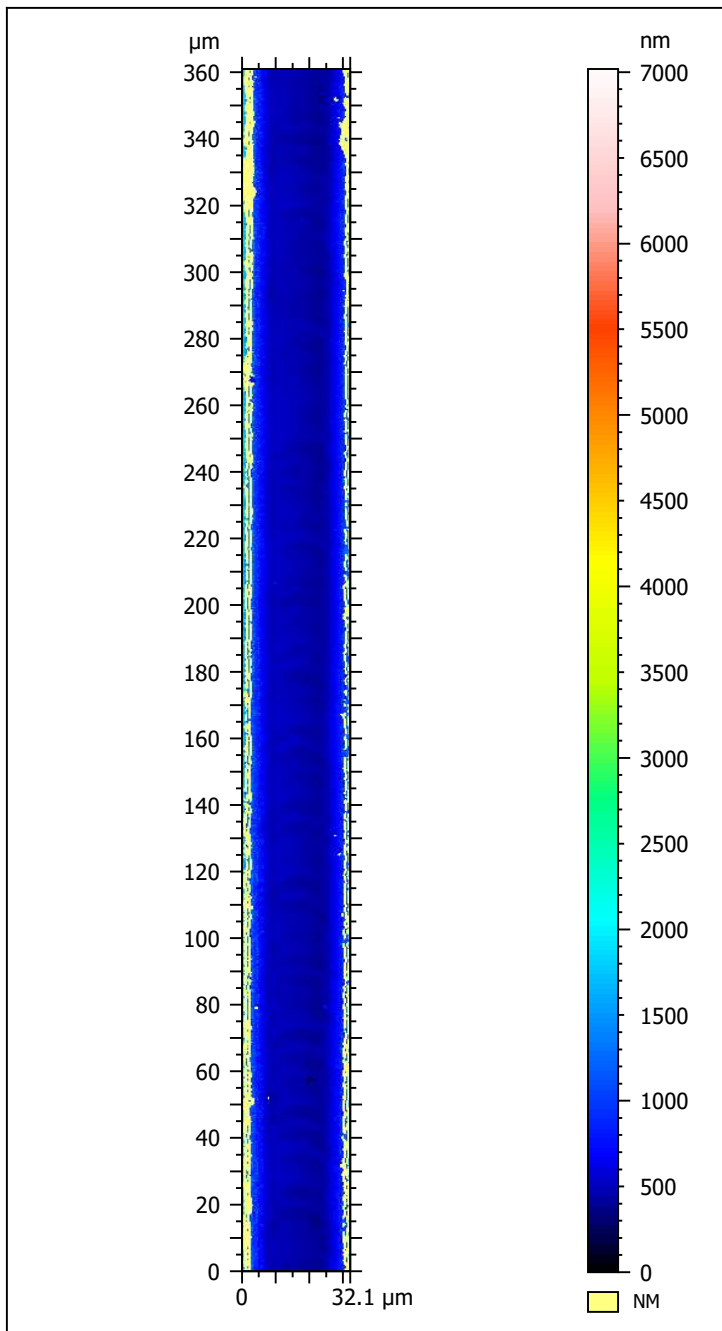
0.2 mm diameter mill 100 mm/min



Measured data



Bottom of channel extracted



ISO 4287

Amplitude parameters - Roughness profile

Rp	35.3 nm	Gaussian filter, 0.08 mm
Rv	42.4 nm	Gaussian filter, 0.08 mm
Rz	77.7 nm	Gaussian filter, 0.08 mm
Rc	42.9 nm	Gaussian filter, 0.08 mm, ISO 4287 w/o amendme...
Rt	83.6 nm	Gaussian filter, 0.08 mm
Ra	14.6 nm	Gaussian filter, 0.08 mm
Rq	17.6 nm	Gaussian filter, 0.08 mm
Rsk	-0.182	Gaussian filter, 0.08 mm
Rku	2.36	Gaussian filter, 0.08 mm

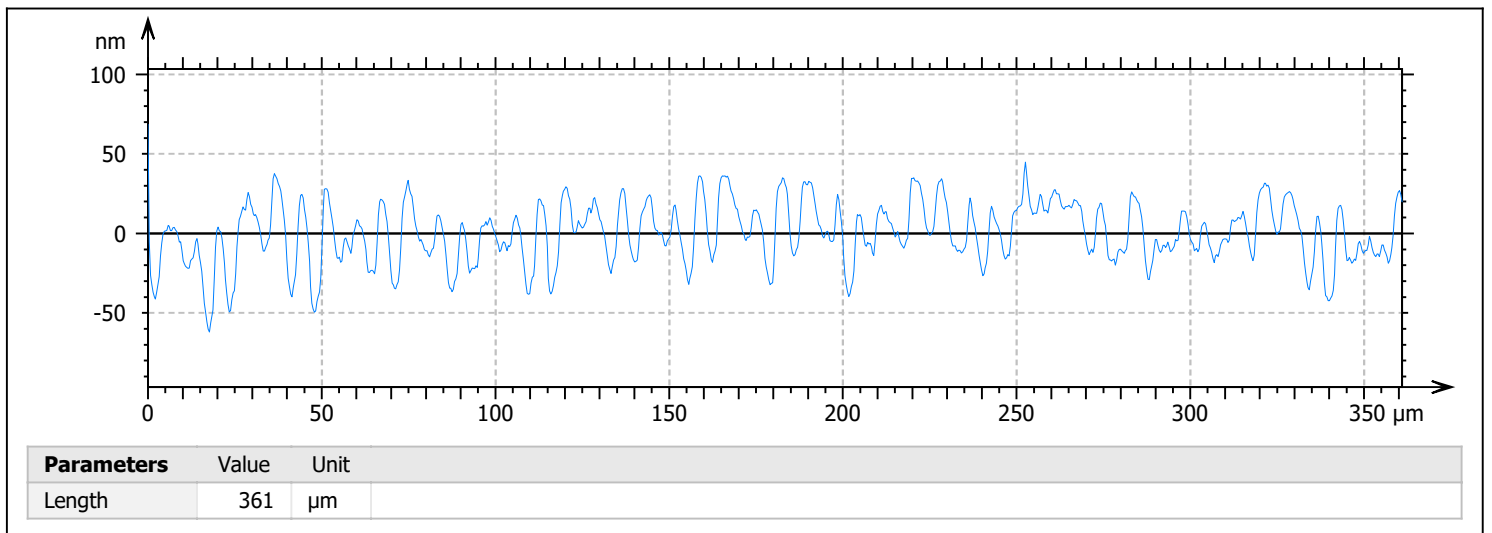
Material Ratio parameters - Roughness profile

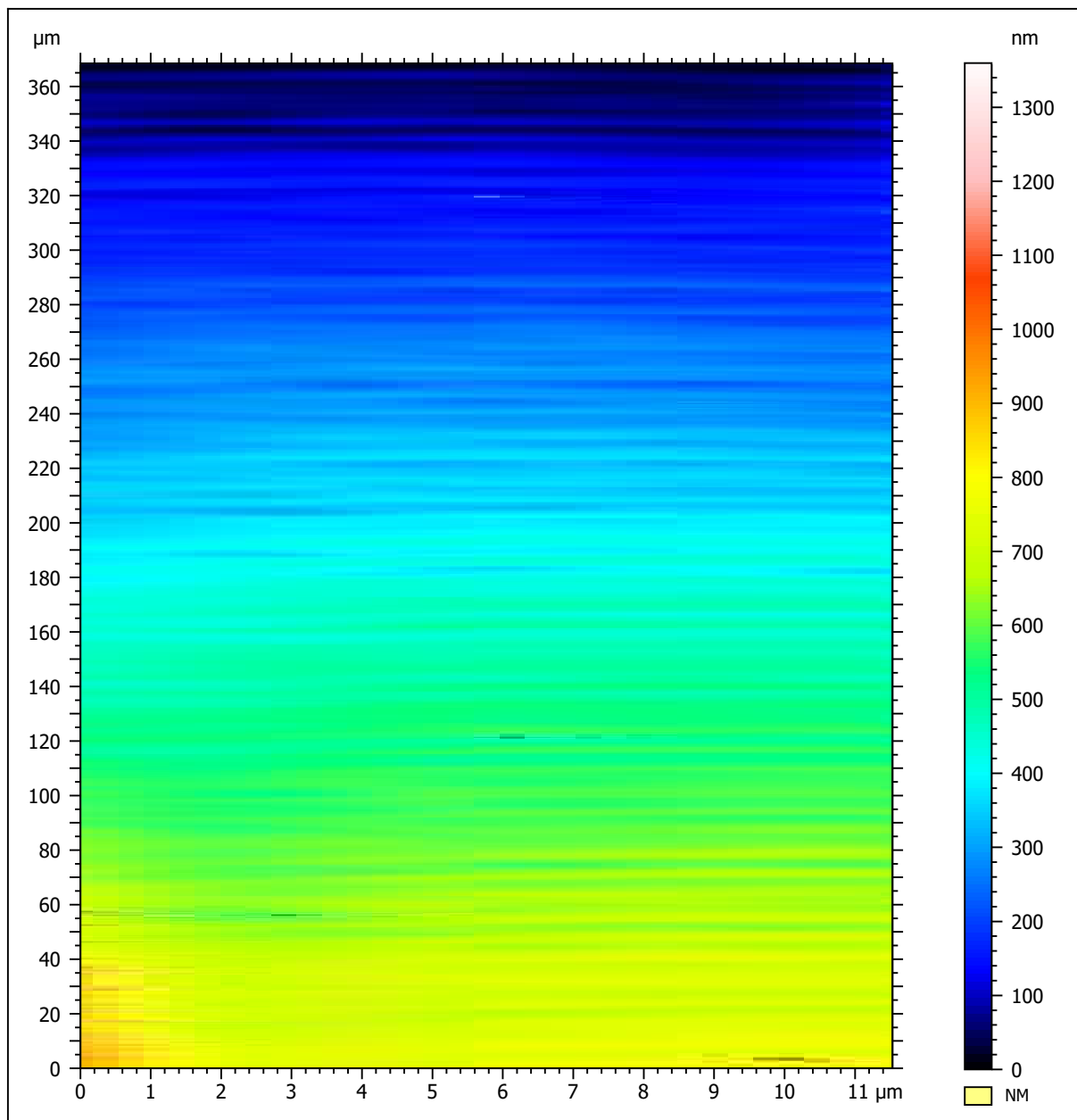
Rmr	100 %	$c = 1000$ nm under the highest peak, Gaussian filt..
Rdc	29.9 nm	$p = 20\%$, $q = 80\%$, Gaussian filter, 0.08 mm

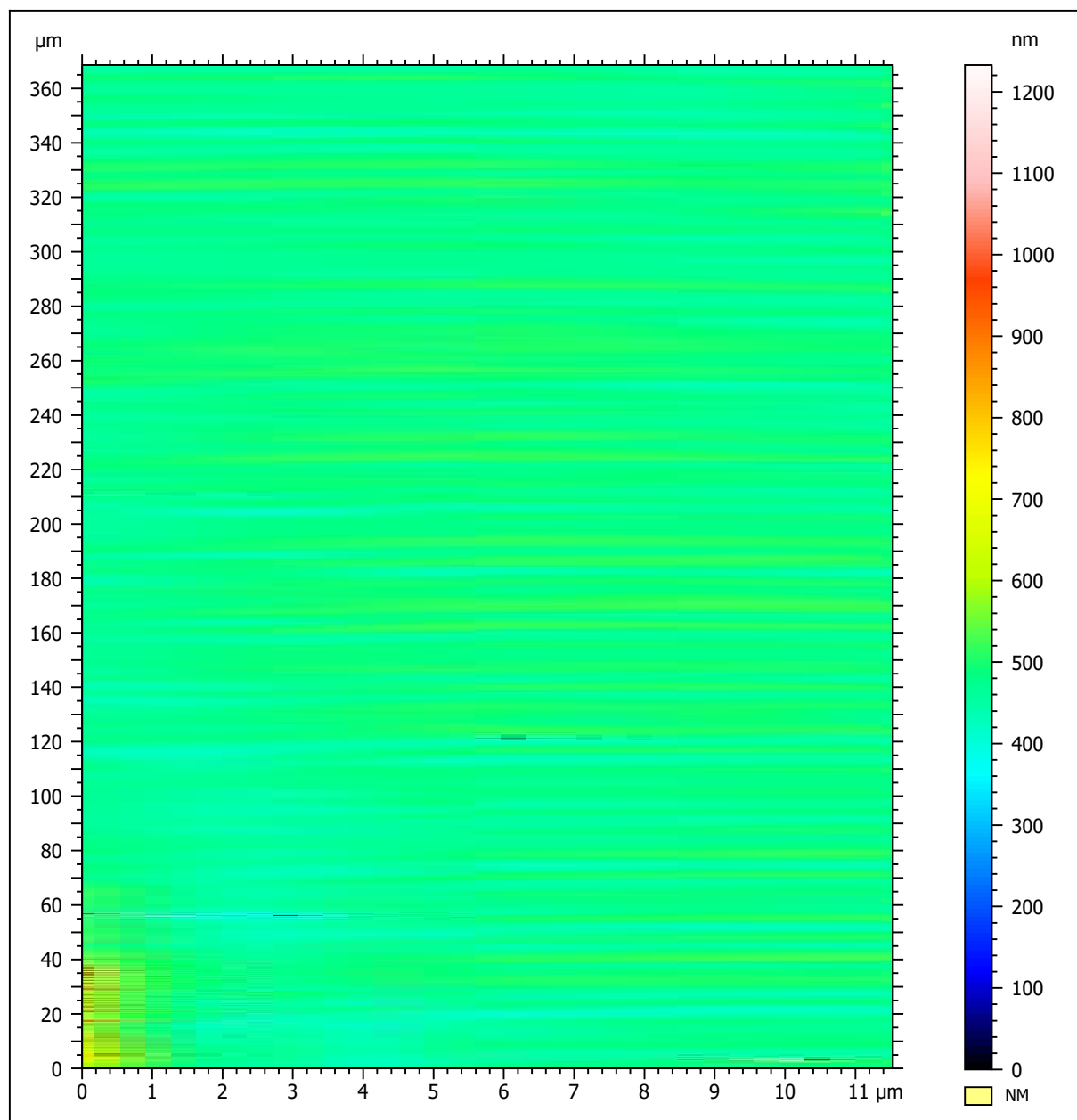
Amplitude parameters - Primary profile

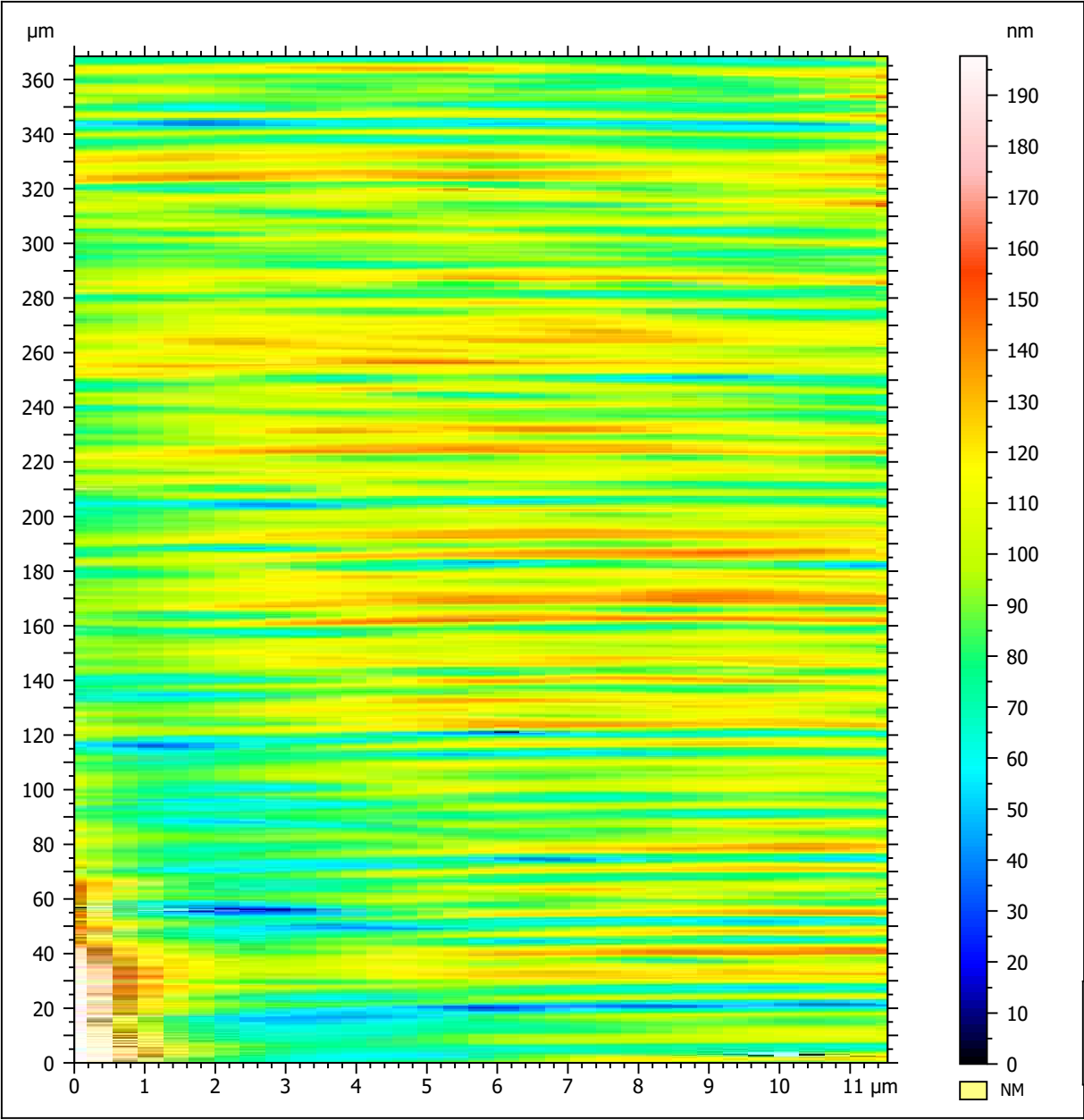
Pa	15.6 nm	
----	---------	--

Levelled

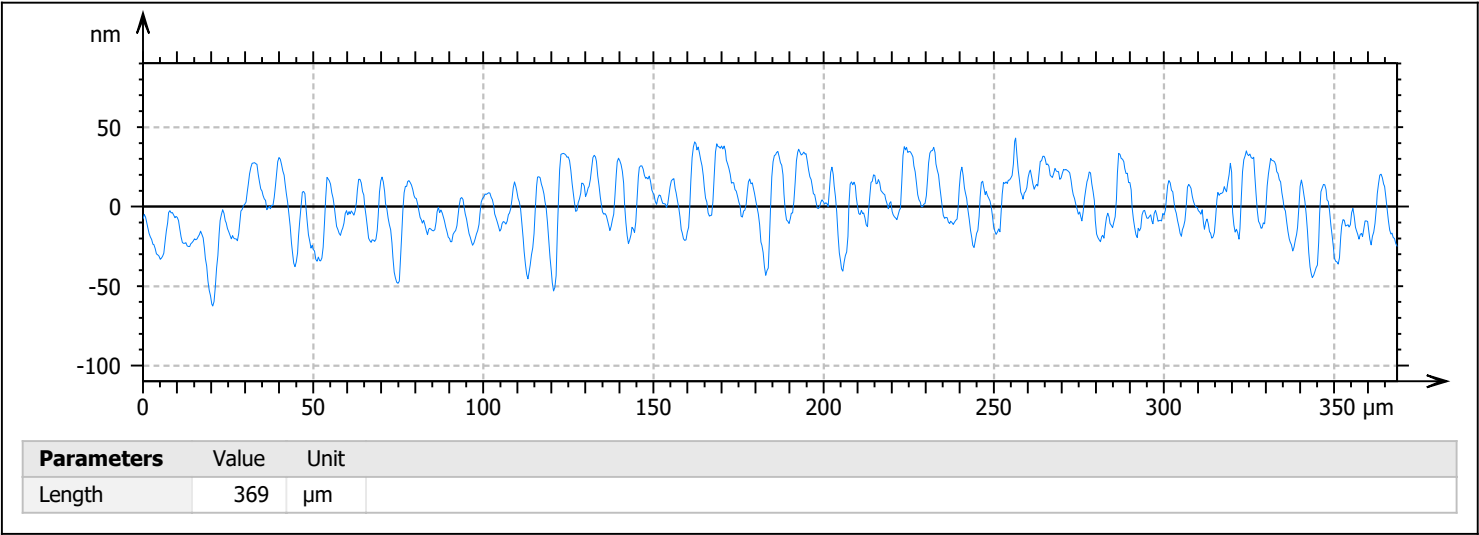








Thresholded



Trace extracted from bottom of channel

ISO 4287			
Amplitude parameters - Roughness profile			
Rp	34.0	nm	<i>Gaussian filter, 0.08 mm</i>
Rv	47.4	nm	<i>Gaussian filter, 0.08 mm</i>
Rz	81.4	nm	<i>Gaussian filter, 0.08 mm</i>
Rc	43.7	nm	<i>Gaussian filter, 0.08 mm, ISO 4287 w/o amendment 2</i>
Rt	89.6	nm	<i>Gaussian filter, 0.08 mm</i>
Ra	14.0	nm	<i>Gaussian filter, 0.08 mm</i>
Rq	17.4	nm	<i>Gaussian filter, 0.08 mm</i>
Rsk	-0.38		<i>Gaussian filter, 0.08 mm</i>
Rku	2.81		<i>Gaussian filter, 0.08 mm</i>
Material Ratio parameters - Roughness profile			
Rmr	100	%	<i>c = 1000 nm under the highest peak, Gaussian filter...</i>
Rdc	29.0	nm	<i>p = 20%, q = 80%, Gaussian filter, 0.08 mm</i>
Amplitude parameters - Primary profile			
Pq	19.4	nm	